

FDMC7696

January 2015

N-Channel PowerTrench[®] MOSFET 30 V, 12 A, 11.5 m Ω

Features

- Max $r_{DS(on)}$ = 11.5 m Ω at V_{GS} = 10 V, I_D = 12 A
- Max $r_{DS(on)} = 14.5 \text{ m}\Omega$ at $V_{GS} = 4.5 \text{ V}$, $I_D = 10 \text{ A}$
- High performance technology for extremely low r_{DS(on)}
- Termination is Lead-free and RoHS Compliant

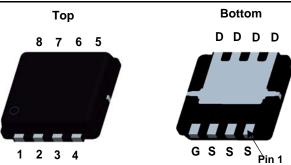
General Description

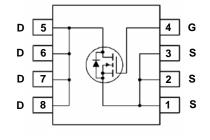
This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced Power Trench® process that has been especially tailored to minimize the on-state resistance. This device is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.

Applications

- DC/DC Buck Converters
- Notebook battery power management
- Load Switch in Notebook







MLP 3.3x3.3

MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter		Ratings	Units	
V_{DS}	Drain to Source Voltage			30	V
V _{DSt}	Drain to Source Transient Voltage (tTransient	< 100 ns)		33	V
V_{GS}	Gate to Source Voltage		(Note 4)	±20	V
	Drain Current -Continuous (Package limited)	T _C = 25°C		20	
	-Continuous (Silicon limited)	T _C = 25°C		38	^
'D	-Continuous	T _A = 25°C	(Note 1a)	12	Α
	-Pulsed			50	
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	21	mJ
В	Power Dissipation	T _C = 25°C		25	W
P_{D}	Power Dissipation	T _A = 25°C	(Note 1a)	2.4	VV
T _J , T _{STG}	Operating and Storage Junction Temperature R	ange		-55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	5.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	53	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC7696	FDMC7696	MLP 3.3x3.3	13 "	12 mm	3000 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		14		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V			1	μΑ
I _{GSS}	Gate to Source Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	nA

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	1.2	2.0	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25 °C		-6		mV/°C
r _{DS(on)} S		V _{GS} = 10 V, I _D = 12 A		8.5	11.5	mΩ
	Static Drain to Source On Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$		11.5	14.5	
	Static Brain to Source Off Nesistance	$V_{GS} = 10 \text{ V, } I_{D} = 12 \text{ A,}$ $T_{J} = 125 ^{\circ}\text{C}$		11.6	15.7	
g _{FS}	Forward Transconductance	V _{DS} = 5 V, I _D = 12 A		45		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 45 V V 0 V		1075	1430	pF
C _{oss}	Output Capacitance	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz		380	505	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 1/11/12		40	55	pF
R_g	Gate Resistance		0.2	1.0	2.0	Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time		9	18	ns
t _r	Rise Time	V _{DD} = 15 V, I _D = 12 A,	2	10	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$	19	33	ns
t _f	Fall Time		2	10	ns
Q_g	Total Gate Charge	V _{GS} = 0 V to 10 V	16	22	nC
Q_g	Total Gate Charge	$V_{GS} = 0 \ V \text{ to 5 V} V_{DD} = 15 \ V,$	8	11	nC
Q _{gs}	Gate to Source Charge	I _D = 12 A	3.2		nC
Q_{gd}	Gate to Drain "Miller" Charge		1.8		nC

Drain-Source Diode Characteristics

V _{SD} Source to Drain Diode Forward Voltage	Source to Drain Diode, Forward Voltage	V _{GS} = 0 V, I _S = 1.9 A (Note 2)	0.75	1.2	V
	$V_{GS} = 0 \text{ V, } I_S = 12 \text{ A}$ (Note 2)	0.84	1.2	, v	
t _{rr}	Reverse Recovery Time	- I _E = 12 A, di/dt = 100 A/μs	25	40	ns
Q _{rr}	Reverse Recovery Charge	- I _F = 12 A, αl/αt = 100 A/μs	9	18	nC

Notes:

Notes. 1. R_{0JA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design.



a. 53 °C/W when mounted on a 1 in² pad of 2 oz copper.



b. 125 °C/W when mounted on a minimum pad of 2 oz copper.

^{2.} Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%. 3. E_{AS} of 21 mJ is based on starting T_J = 25 °C, L = 0.3 mH, I_{AS} = 12 A, V_{DD} = 27 V, V_{GS} = 10 V. 4. As an N-ch device, the negative Vgs rating is for low duty cycle pulse ocurrence only. No continuous rating is implied.

Typical Characteristics $T_J = 25$ °C unless otherwise noted

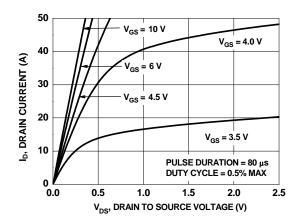


Figure 1. On Region Characteristics

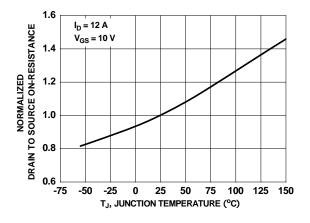


Figure 3. Normalized On Resistance vs Junction Temperature

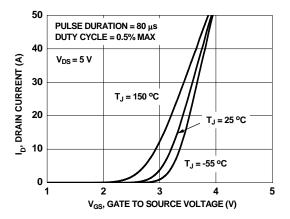


Figure 5. Transfer Characteristics

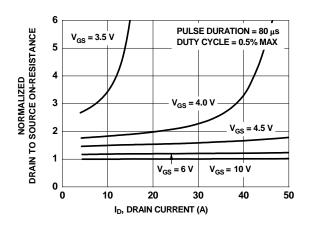


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

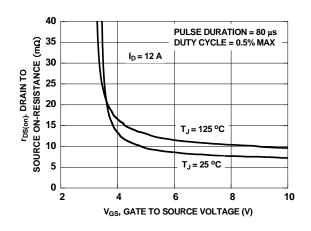


Figure 4. On-Resistance vs Gate to Source Voltage

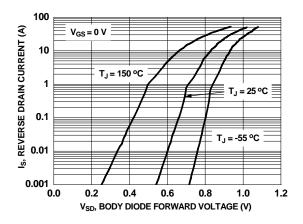


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics $T_J = 25$ °C unless otherwise noted

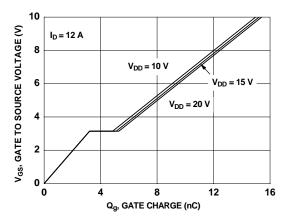


Figure 7. Gate Charge Characteristics

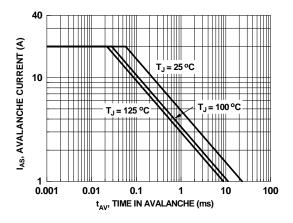


Figure 9. Unclamped Inductive Switching Capability

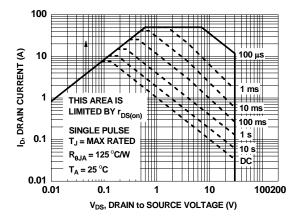


Figure 11. Forward Bias Safe Operating Area

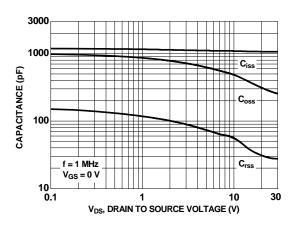


Figure 8. Capacitance vs Drain to Source Voltage

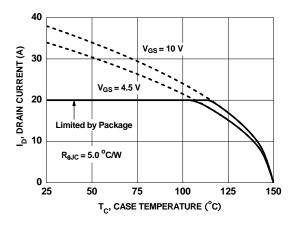


Figure 10. Maximum Continuous Drain Current vs Case Temperature

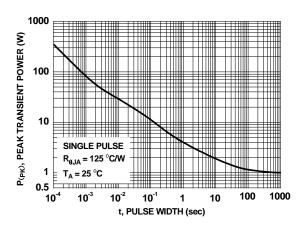


Figure 12. Single Pulse Maximum Power Dissipation



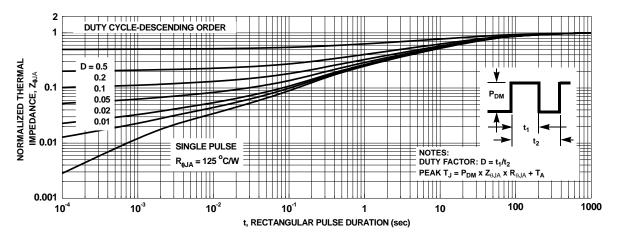
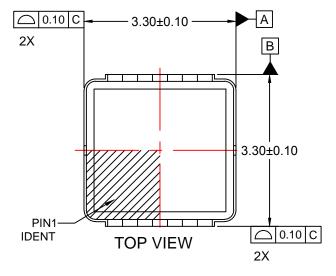
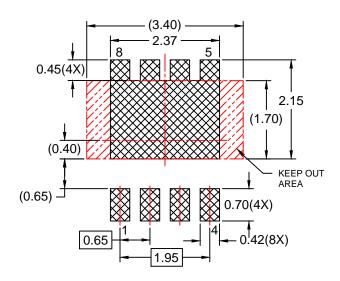
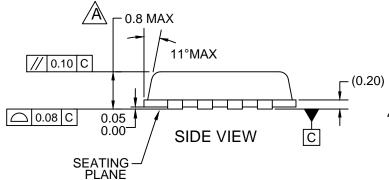


Figure 13. Junction-to-Ambient Transient Thermal Response Curve



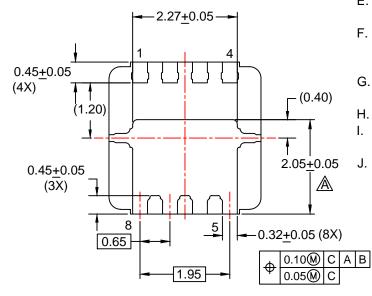




RECOMMENDED LAND PATTERN

NOTES:

- EXCEPT AS NOTED, PACKAGE CONFORMS TO JEDEC REGISTRATION MO-240 VARIATION BA..
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994.
- D. SEATING PLANE IS DEFINED BY TERMINAL TIPS ONLY
- E. BODY DIMENSIONS DO NOT INCLUDE MOLD FLASH PROTRUSIONS NOR GATE BURRS.
- F. FLANGE DIMENSIONS INCLUDE INTERTERMINAL FLASH OR PROTRUSION. INTERTERMINAL FLASH OR PROTRUSION SHALL NOT EXCEED 0.25MM PER SIDE.
- G. IT IS RECOMMENDED TO HAVE NO TRACES OR VIA WITHIN THE KEEP OUT AREA.
- H. DRAWING FILENAME: MKT-MLP08Trev3.
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- J. FAIRCHILD SEMICONDUCTOR.



BOTTOM VIEW





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Definition of Terms

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Datasheet Identification	Product Status	Definition			
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.			
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.			
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